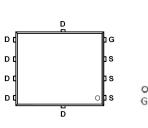


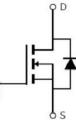
SMS006N02J7

Main Product Characteristics:

V _{DSS}	60V
R _{DS} (on)	1.9mΩ (typ.)
ID	200A







PDFN5x6-8L

Pin Assignments

Schematic Diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute Max Rating:

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V ①	200	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V ①	160	A
Ідм	Pulsed Drain Current ②	800	
P _D @T _C = 25°C	Power Dissipation ③	156	W
V _{DS}	Drain-Source Voltage	60	V
V _{GS}	Gate-to-Source Voltage	± 20	V
Eas	Single Pulse Avalanche Energy @ L=0.5mH	306	mJ
Tj Tstg	Operating Junction and Storage Temperature Range	-55 to +150	°C



Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
Rejc	Junction-to-case ③	_	0.8	°C/W
R _{0JA}	Junction-to-ambient (t $\leq 10s$) ④		42	°C/W

Electrical Characterizes @TA=25°C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	60	_	—	V	V _{GS} = 0V, I _D = 250µA
R _{DS(on)}	Static Drain-to-Source on-resistance	—	1.9	2.5	mΩ	V_{GS} =10V,I _D = 30A
			2.6	3.4		V _{GS} =4.5V,I _D = 20A
$V_{GS(th)}$	Gate threshold voltage	1	_	2.5	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$
IDSS	Drain-to-Source leakage current		_	1	μA	$V_{DS} = 60V, V_{GS} = 0V$
			_	100	•	V _{GS} =20V
I _{GSS}	Gate-to-Source forward leakage		_	-100	nA	V _{GS} = -20V
Ciss	Input capacitance		5440	_		V _{GS} = 0V
Coss	Output capacitance		2200	_	pF	V _{DS} = 25V
Crss	Reverse transfer capacitance		135	_		f = 1MHz
Qg	Total gate charge		100	_		I _D = 30A,
Q _{gs}	Gate-to-Source charge		15	_	nC	V _{DS} =30V,
Q_{gd}	Gate-to-Drain("Miller") charge	—	20	—		V _{GS} = 10V
t _{d(on)}	Turn-on delay time	_	15	—		
tr	Rise time	_	38	_		V_{GS} =10V, V_{DD} =30V,
$t_{d(off)}$	Turn-Off delay time	_	75	—	ns	R _{GEN} =3Ω,I _D =30A
t _f	Fall time		95	_		

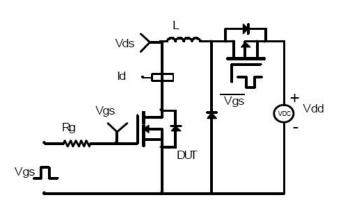
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			200	А	MOSFET symbol
Is	(Body Diode)			200	A	showing the (
Іѕм	Pulsed Source Current	_		800	А	integral reverse
	(Body Diode)					p-n junction diode.
V _{SD}	Diode Forward Voltage	_	—	1.2	V	I _S =30A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	_	54		ns	T_J = 25°C, I_F =30A, di/dt =
Qrr	Reverse Recovery Charge	_	60		nC	100A/µs

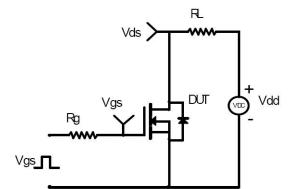


Test Circuits and Waveforms

EAS Test Circuit:

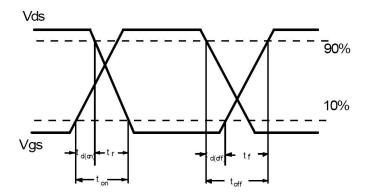


Switching Time Test Circuit:



Switching Waveforms:

Gate Charge Test Circuit:

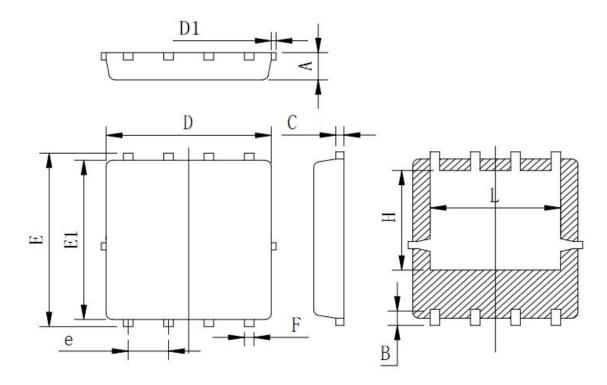


Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- (④The value of R_{θJA} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



Mechanical Data:



Symbol	Min	Тур	Max
A	0.90	0.95	1.00
В	0.48	0.58	0.68
С	0.20	0.254	0.30
D	5.00	5.20	5.40
D1			0.15
E	5.90	6.05	6.20
E1	5.40	5.55	5.70
e	1.22	1.27	1.32
F	0.25	0.30	0.35
Н	3.27	3.47	3.67
L	3.80	4.00	4.20



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